

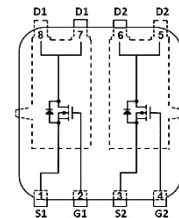
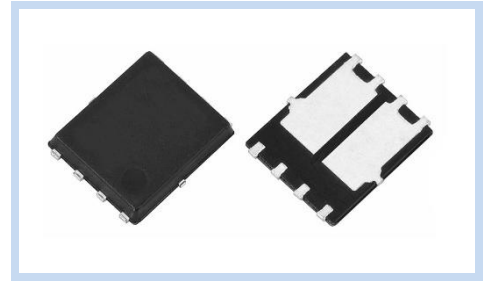
Dual N-Channel MOSFET AEC-Q101 60V 30A 23W DFN5×6-8L

MFT62N30D56A

MERITEK

FEATURE

- $R_{DS(ON)} < 15m\Omega$, $V_{GS}=10V$, $I_D=10A$
- $R_{DS(ON)} < 23m\Omega$, $V_{GS}=4.5V$, $I_D=8A$
- Low On-Resistance
- Low Input Capacitance
- Application: DC-DC Converter, Switching Power Supply, High-Side Load Switching, Motor Control
- AEC-Q101 Qualified



MECHANICAL DATA

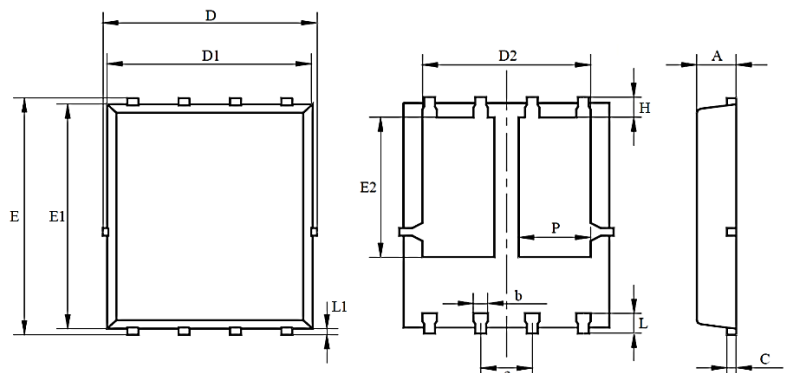
- Case: DFN5×6-8L Package
- Terminals: Solderable per MIL-STD-750, Method 2026

MAXIMUM RATINGS

Parameter		Symbol	Value	Unit
Drain-Source Voltage		V_{DS}	60	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current – Continuous	$T_C = 25^\circ C$	I_D	30	A
	$T_C = 100^\circ C$		21	
Drain Current – Pulsed	$T_C = 25^\circ C$	I_{DM}	100	A
Power Dissipation	$T_C = 25^\circ C$	P_D	23	W
Single Pulse Avalanche Energy		E_{AS}	6.9	mJ
Avalanche Current		I_{AS}	11.7	A
Thermal Resistance Junction to Case		$R_{\theta JC}$	6.5	$^\circ C/W$
Thermal Resistance Junction to Ambient		$R_{\theta JA}$	60	$^\circ C/W$
Operating Junction and Storage Temperature		T_J, T_{STG}	-55 to +175	$^\circ C$

DIMENSIONS

Item	Min (mm)	Max (mm)
A	0.90	1.10
b	0.33	0.51
C	0.20	0.30
D	4.80	5.00
D2	3.61	3.96
E	5.90	6.10
E1	5.70	5.80
E2	3.38	3.78
e	1.27	
L	0.51	0.71
L1	0.06	0.20
H	0.41	0.61
P	1.56	1.73



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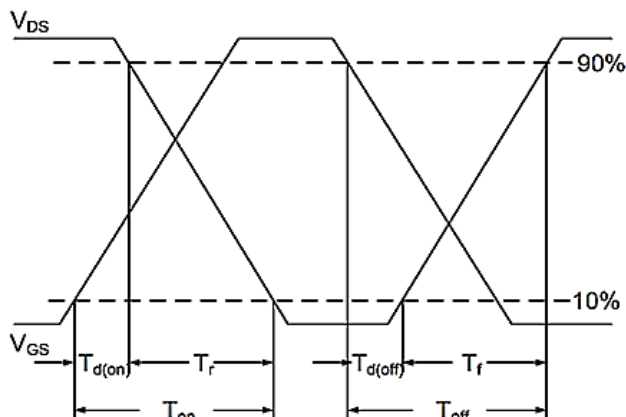
ELECTRICAL CHARACTERISTICS

Off Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Drain-Source Breakdown Voltage	$I_D=10\text{mA}$	BV_{DSS}	60	--	--	V
Drain-Source Leakage Current	$V_{DS}=48\text{V}$	I_{DSS}	--	--	1	μA
Gate-Source Leakage Current	$V_{GS}=\pm 16\text{V}$	I_{GSS}	--	--	± 100	nA
On Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=10\text{A}$	$R_{DS(ON)}$	--	13.0	15.0	m Ω
	$V_{GS}=4.5\text{V}, I_D=8\text{A}$		--	--	23.0	
Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=250\mu\text{A}$	$V_{GS(th)}$	1.2	--	2.5	V
Dynamic Characteristics	Conditions	Symbol	Min	Typ.	Max	Unit
Total Gate Charge	$V_{DS}=30\text{V}, V_{GS}=4.5, I_D=10\text{A}$	Q_g	--	6.4	--	nC
			--	12.4	--	
Gate-Source Charge	$V_{DS}=30\text{V}, V_{GS}=10, I_D=10\text{A}$	Q_{gs}	--	2.0	--	
Gate-Drain Charge		Q_{gd}	--	3.3	--	
Turn-On Delay Time	$V_{DS}=30\text{V}, V_{GS}=10\text{V}, R_G=3.3\Omega, I_D=10\text{A}$	$T_{d(on)}$	--	7.0	--	ns
Rise Time		T_r	--	15.0	--	
Turn-Off Delay Time		$T_{d(off)}$	--	7.0	--	
Fall Time		T_f	--	1.5	--	
Input Capacitance	$V_{DS}=30\text{V}, V_{GS}=0\text{V}, F=1\text{MHz}$	C_{iss}	--	561	--	pF
Output Capacitance		C_{oss}	--	218	--	
Reverse Transfer Capacitance		C_{rss}	--	19	--	
Gate Resistance	$V_{DS}=0\text{V}, V_{GS}=0\text{V}, F=1\text{MHz}$	R_g	--	1.1	--	Ω
Drain-Source Body Diode	Conditions	Symbol	Min	Typ.	Max	Unit
Diode Forward Current	$T_C=25^\circ\text{C}$	I_S	--	--	30	A
Pulse Diode Forward Current		I_{SM}	--	--	100	
Diode Forward Voltage	$V_{GS}=0\text{V}, I_S=10\text{A}$	V_{SD}	--	--	1.3	V
Reverse Recovery Time	$I_S=10\text{A}, dI_S/dt=100\text{A}/\mu\text{s}$	T_{rr}	--	14.8	--	ns
Reverse Recovery Charge		Q_{rr}	--	5.4	--	nC

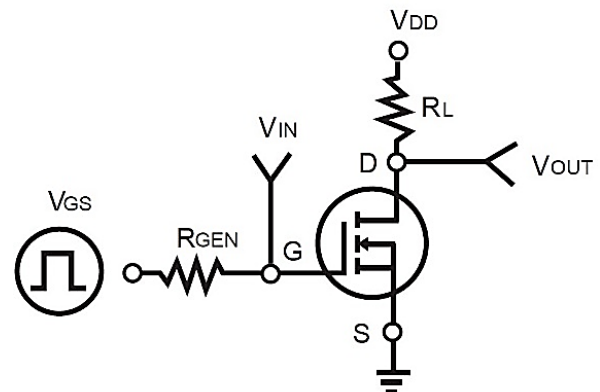
Note:

1. Pulse width $\leq 100\mu\text{s}$, duty cycle $\leq 2\%$
2. Essentially independent of operating temperature typical characteristics
3. Guaranteed by design, not test in mass production
4. $R_{\theta JA}$ and $R_{\theta JC}$ are the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. Mounted on a 1 inch² with 2oz. square pad of copper.
5. The test condition is $L=0.1\text{mH}$, $I_{AS}=5.6\text{A}$, $V_{DD}=30\text{V}$, $V_{GS}=10\text{V}$, Starting $T_J=25^\circ\text{C}$.

Switching Time Waveform

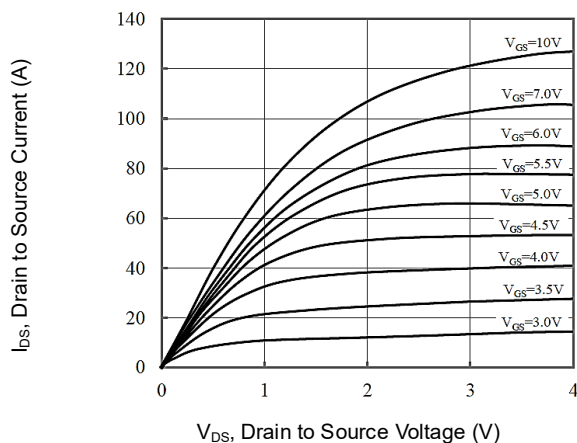


Switching Test Circuit

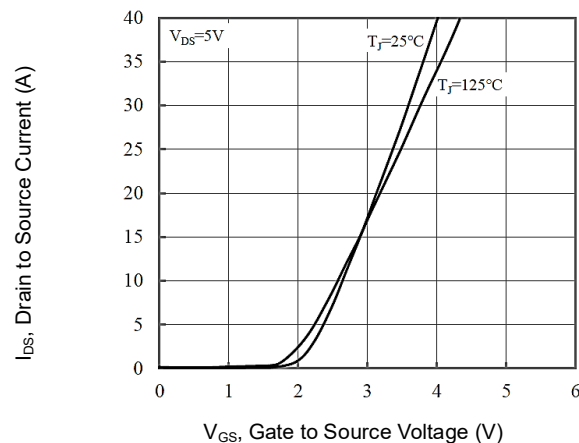


CHARACTERISTIC CURVES

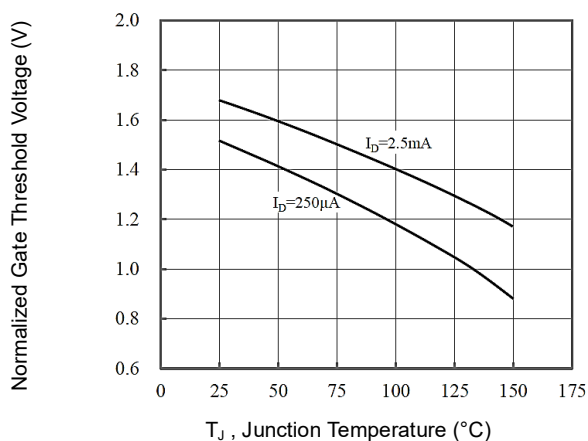
On-Region Characteristics



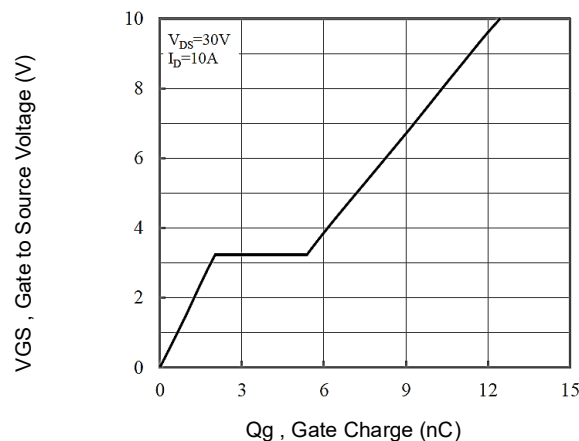
Transfer Characteristics



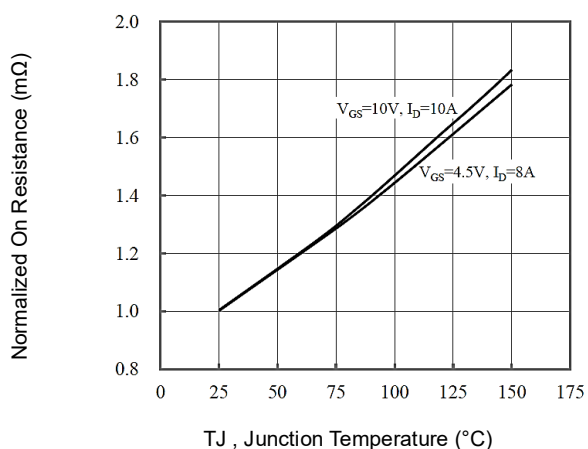
Normalized V_{th} vs. T_J



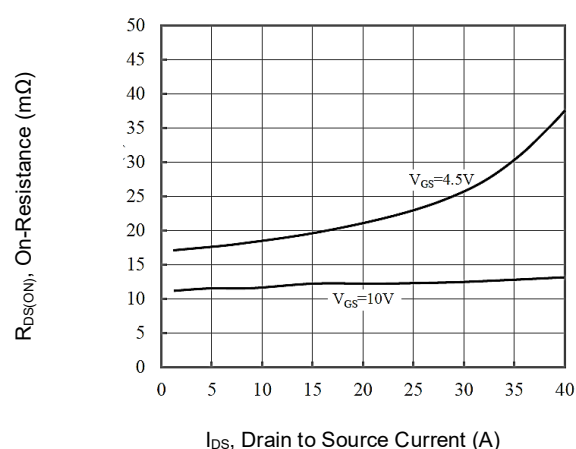
Gate Charge Waveform



Normalized $R_{DS(on)}$ vs. T_J

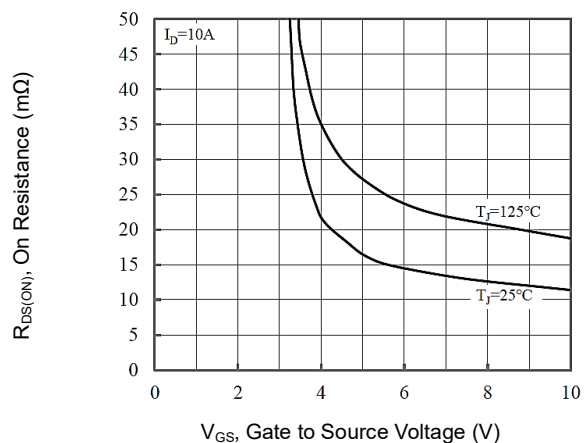


On-Resistance vs. Drain Current

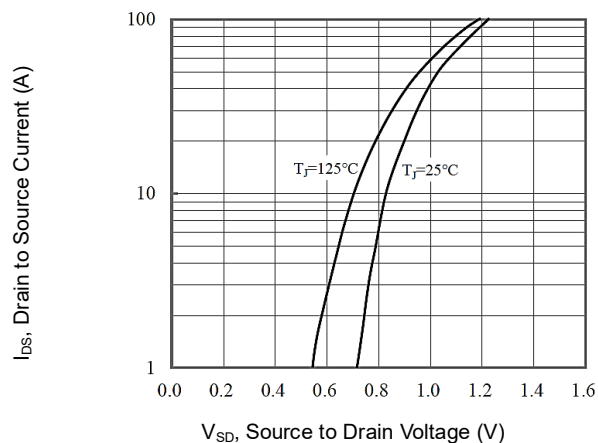


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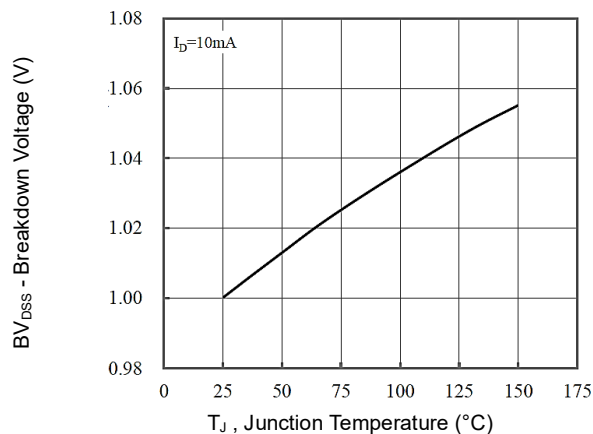
On-Resistance Variation with V_{GS}



Body Diode



Breakdown Voltage vs Junction Temperature



Capacitance vs. Drain-Source Voltage

